

STW45NM60D

N-channel 600 V, 0.09 Ω, 45 A TO-247 FDmesh™ Power MOSFET (with fast diode)

Features

Туре	V _{DSS} (@Tjmax)	R _{DS(on)}	I _D
STW45NM60D	650 V	< 0.11 Ω	45 A

- High dv/dt and avalanche capabilities
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

Application

Switching applications

Description

The FDmesh[™] associates all advantages of reduced on-resistance and fast switching with an intrinsic fast-recovery body diode. It is therefore strongly recommended for bridge topologies, in particular ZVS phase-shift converters.

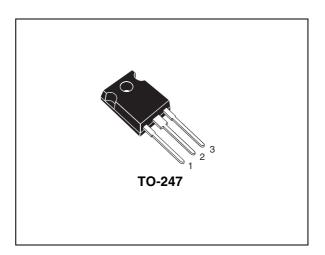


Figure 1. Internal schematic diagram

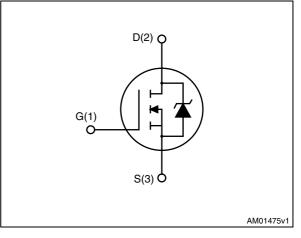


Table 1.Device summary

Order code	Marking	Package	Packaging
STW45NM60D	W45NM60D	TO-247	Tube

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Electrical ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (VGs = 0)	600	V
V _{GS}	Gate- source voltage	±30	V
Ι _D	Drain current (continuous) at $T_C = 25 \ ^{\circ}C$	45	А
I _D	Drain current (continuous) at T _C = 100 °C	28	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	180	А
P _{TOT}	Total dissipation at $T_C = 25 \ ^{\circ}C$	417	W
	Derating factor	3.33	W/°C
dv/dt (2)	Peak diode recovery voltage slope	20	V/ns
T _{stg}	Storage temperature	-65 to 150	°C
Тj	Max. operating junction temperature	150	°C

1. Pulse width limited by safe operating area

2. $~I_{SD}~\leq~45$ A, di/dt $~\leq~400$ A/µs, $V_{DD}~\leq~80\%~V_{(BR)DSS}$

Table 3. Thermal data

Symbol	Parameter	Value	Unit
Rthj-case	Thermal resistance junction-case	0.3	°C/W
Rthj-amb	Thermal resistance junction-amb	30	°C/W
Τ _Ι	Maximum lead temperature for soldering purpose	300	°C

	Table 4.	Avalanche	characteristics
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Sym	bol	Parameter	Max value	Unit
I _{AS}	S	Avalanche current, repetitive or not-repetitive (pulse width limited by T _j max)	15	А
E _A	AS	Single pulse avalanche energy (starting $T_j = 25 \text{ °C}$, $I_D = I_{AS}$, $V_{DD} = 35 \text{ V}$)	850	mJ



2 Electrical characteristics

(T_{CASE} = 25 °C unless otherwise specified)

Tuble 0.	01401101010					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_{D} = 250 \ \mu A, \ V_{GS} = 0$	600			V
I _{DSS}	Zero gate voltage	V _{DS} = Max rating			10	μA
'DSS	Drain current (V _{GS} = 0)	V_{DS} = Max rating, T_{C} = 125 °C			100	μA
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ±30 V			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 22.5 A		0.09	0.11	Ω

Table 5. On/off states

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
9 _{fs} ⁽¹⁾	Forward transconductance	$V_{DS} > I_{D(on)} \times R_{DS(on)max,}$ $I_{D}= 22.5 \text{ A}$	-	30	-	S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 25 V, f = 1 MHz, V _{GS} = 0	-	3500 1400 76	-	pF pF pF
C _{oss eq.} ⁽²⁾	Equivalent output capacitance	$V_{GS} = 0, V_{DS} = 0$ to 480 V	-	520	-	рF
R _G	Gate input resistance	f=1 MHz Gate DC Bias = 0 test signal level = 20 mV open drain	-	2	-	Ω
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 480 \text{ V}, \text{ I}_{D} = 45 \text{ A},$ $V_{GS} = 10 \text{ V}$ Figure 15	-	96 20 60	-	nC nC nC

1. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5%.

2. $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}



	ownerning times					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on delay time Rise time	$V_{DD} = 300 \text{ V}, \text{ I}_{D} = 22.5 \text{ A}$ $R_{G} = 4.7 \Omega \text{ V}_{GS} = 10 \text{ V}$	-	25 70	-	ns ns
t _{d(off)} t _f	Turn-off delay time Fall time	Figure 14	-	60 66	-	ns ns

Table 7.Switching times

Table 8. Source drain diode

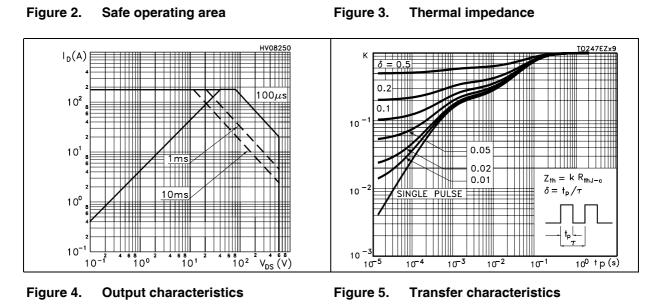
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		-		45	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		180	А
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 45 A, V _{GS} = 0	-		1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 45 A, di/dt = 100 A/μs, V _{DD} = 100 V <i>Figure 16</i>	-	200 2 17		ns μC Α
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 45 A, di/dt = 100 A/μs, V _{DD} = 100 V, T _j = 150 °C <i>Figure 16</i>	-	300 4 23		ns μC Α

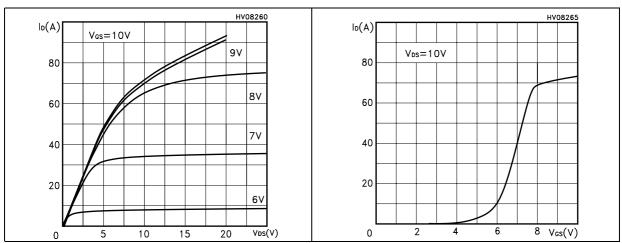
1. Pulse width limited by safe operating area

2. Pulsed: Pulse duration = $300 \ \mu s$, duty cycle 1.5%.

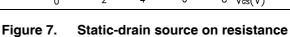


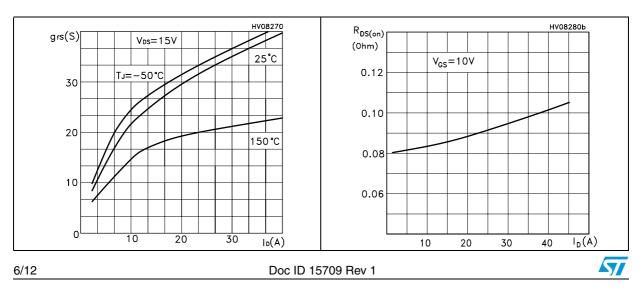
2.1 Electrical characteristics (curves)











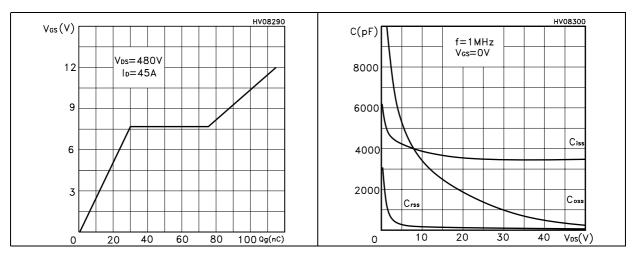


Figure 8. Gate charge vs gate-source voltage Figure 9. **Capacitance variations**

Figure 10. Normalized gate threshold voltage Figure 11. vs temperature

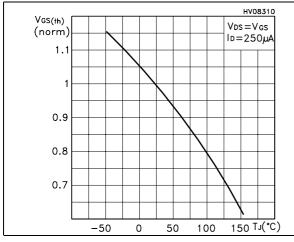
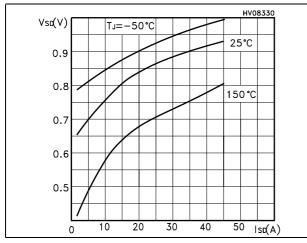
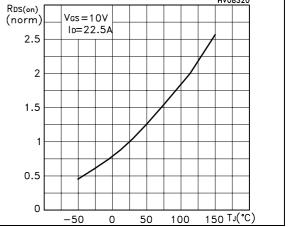


Figure 12. Source-drain diode forward characteristics



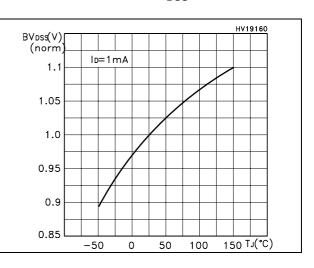
HV08320 RDS(on) Vgs=10V

temperature



Normalized on resistance vs

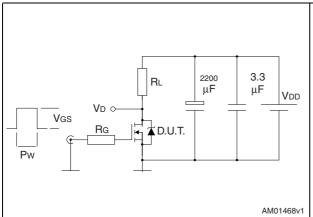
Figure 13. Normalized BV_{DSS} vs temperature

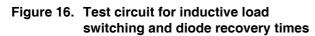


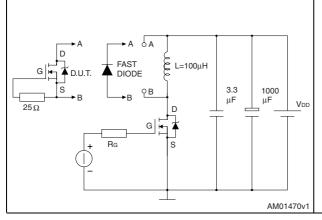


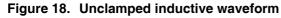
3 Test circuit

Figure 14. Switching times test circuit for resistive load









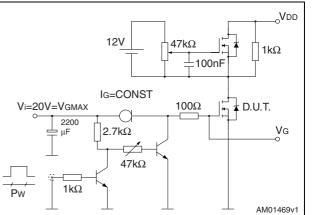
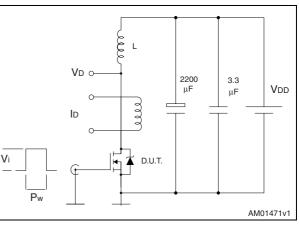


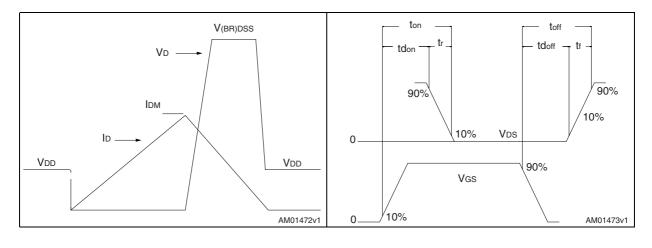
Figure 15. Gate charge test circuit

Figure 17. Unclamped inductive load test











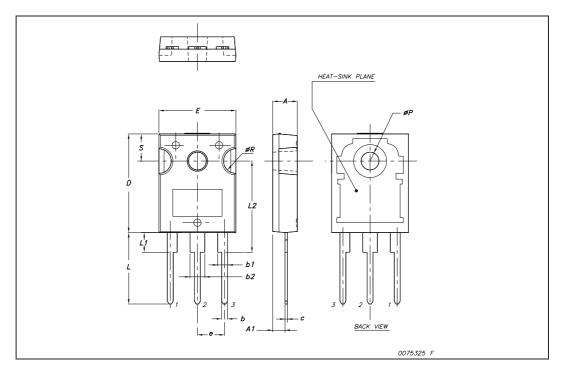
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4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.



TO-247 Mechanical data				
Dim.	mm.			
	Min.	Тур	Max.	
А	4.85		5.15	
A1	2.20		2.60	
b	1.0		1.40	
b1	2.0		2.40	
b2	3.0		3.40	
С	0.40		0.80	
D	19.85		20.15	
E	15.45		15.75	
е		5.45		
L	14.20		14.80	
L1	3.70		4.30	
L2		18.50		
øP	3.55		3.65	
øR	4.50		5.50	
S		5.50		



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5 Revision history

Table 9.Document revision history

Date	Revision	Changes
08-Jun-2009	1	First release



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